

## Product description

# PointProbe® Plus Contact Mode

The PointProbe® Plus (PPP) combines high application versatility and compatibility with most commercial SPMs. The typical AFM tip radius of less than 7 nm and the minimized variation in AFM tip shape provide reproducible images and enhanced resolution.

**NANOSENSORS™ PPP-CONT** AFM probes are designed for contact mode (repulsive mode) AFM imaging. This AFM probe can also be used for force-distance spectroscopy mode or pulsed force mode (PFM). The CONT type is optimized for high sensitivity due to a low force constant.

## The AFM probe offers unique features:

- guaranteed AFM tip radius of curvature < 10 nm
- AFM tip height 10 - 15 µm
- highly doped silicon to dissipate static charge
- chemically inert
- high mechanical Q-factor for high sensitivity

This AFM probe features alignment grooves on the back side of the holder chip. These grooves fit to the NANOSENSORS Alignment Chip.

## Cantilever data:

Property	Nominal Value	Specified Range
Resonance Frequency [kHz]	13	6 - 21
Force Constant [N/m]	0.2	0.02 - 0.77
Length [µm]	450	440 - 460
Mean Width [µm]	50	42.5 - 57.5
Thickness [µm]	2	1 - 3

## Order codes and shipping units:

Order Code	AFM probes per pack	Data sheet
PPP-CONT-10	10	of all probes
PPP-CONT-20	20	of all probes
PPP-CONT-50	50	.....
PPP-CONT-W	380	of up to 32 probes